

Form PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE				ATTY. DOCKET NO. 1012-02		SERIAL NO. 10/031,426	
LIST OF PRIOR ART CITED BY APPLICANT <small>(Use several sheets if necessary)</small>				APPLICANTS Chikara Kami et al.		<div style="border: 1px solid black; padding: 5px; display: inline-block;"> RECEIVED JUN 17 2004 </div>	
				FILING DATE January 18, 2002			
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL*		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
DY	AA	4,838,955	06/13/89	Arie B.C. Edelman et al.	—	—	
	AB	5,123,969	06/23/92	Tung-Sheng Chou	—	—	
	AC	5,405,463	04/11/95	Takayoshi Shimomura et al.	—	—	
	AD	5,582,658	12/10/96	Susumu Masui et al.	—	—	
	AE	5,690,755	11/25/97	Naoki Yoshinaga et al.	—	—	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
DY	AF	JP 55-141526	11/05/80	Japan	—	—	Abstract only
	AG	JP 60-052528	03/25/85	Japan	—	—	Abstract only
	AH	JP 60-145355	07/31/85	Japan	—	—	Abstract only
	AI	JP 61-272323	12/02/86	Japan	—	—	Abstract only
	AJ	EP 0 429 094 A1	05/29/91	Europe	—	—	x
	AK	JP 04-074824	03/10/92	Japan	—	—	Abstract only
	AL	EP 0 510 718 A2	10/28/92	Europe	—	—	x
	AM	EP 0 608 430 A1	08/03/94	Europe	—	—	x
	AN	EP 0 612 857 A1	08/31/94	Europe	—	—	x
	AO	JP 07-090482	04/04/95	Japan	—	—	Abstract only
	AP	EP 0 659 890 A2	06/28/95	Europe	—	—	x
	AQ	EP 0 769 565 A1	04/23/97	Europe	—	—	x
	AR	EP 0 943 696 A1	09/22/99	Europe	—	—	x
	AS	EP 1 002 884 A1	05/24/00	Europe	—	—	x
	EXAMINER <i>Deborah Yee</i>				DATE CONSIDERED <i>8-26-04</i>		
<p>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered.</p> <p>Include copy of this form with next communication to Applicant.</p>							